

20th International Workshop on DEPFET Detectors and Applications

Friday, 13 May 2016

Lab Tests: Pilot Testing in the Lab - Tagungsraum (09:00 - 10:30)

-Conveners: Christian Koffmane

time	[id] title	presenter
09:00	[79] Hybrid 5 tests: Lab characterization and Irradiations	PASCHEN, Botho
09:20	[81] ASIC optimization using DEPFET transistors as current source	Mr SCHREECK, Harrison
09:40	[82] PXD9 - Module Testing after SMD Assembly	Mr BORONAT AREVALO, Marçà
09:55	[83] PXD9 Pilot - Gated Mode Testing	KOFFMANE, Christian